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infineon

MOSFET

Metal Oxide Semiconductor Field Effect Transistor

OptiMOS™

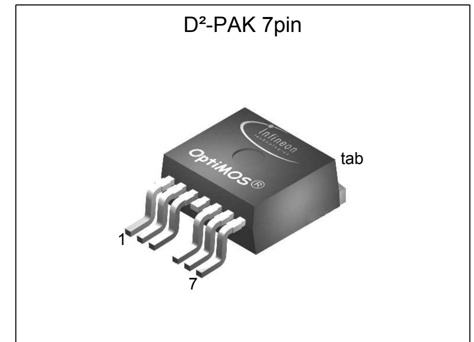
OptiMOS™ 5 Power-Transistor, 80 V
IPB015N08N5

Data Sheet

Rev. 2.1
Final

Power Management & Multimarket

1 Description



Features

- Ideal for high frequency switching and sync. rec.
- Optimized technology for DC/DC converters
- Excellent gate charge x $R_{DS(on)}$ product (FOM)
- Very low on-resistance $R_{DS(on)}$
- N-channel, normal level
- 100% avalanche tested
- Pb-free plating; RoHS compliant
- Qualified according to JEDEC[1] for target applications
- Halogen-free according to IEC61249-2-21

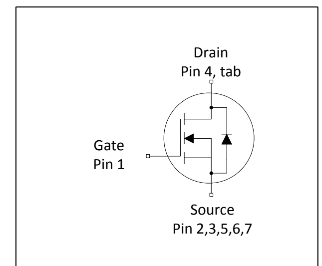


Table 1 Key Performance Parameters

Parameter	Value	Unit
V_{DS}	80	V
$R_{DS(on),max}$	1.5	mΩ
I_D	180	A
Q_{oss}	207	nC
Q_G(0V..10V)	178	nC

Type / Ordering Code	Package	Marking	Related Links
IPB015N08N5	PG-TO263-7	015N08N5	-

[1] J-STD20 and JESD22

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2 Maximum ratings

at T_A=25 °C, unless otherwise specified

Table 2 Maximum ratings

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Continuous drain current	I_D	- -	- -	180 180	A	T_C=25 °C T_C=100 °C
Pulsed drain current[1]	$I_{D,pulse}$	-	-	720	A	T_C=25 °C
Avalanche energy, single pulse[2]	E_{AS}	-	-	1230	mJ	I_D=100 A, R_{GS}=25 Ω
Gate source voltage	V_{GS}	-20	-	20	V	-
Power dissipation	P_{tot}	-	-	375	W	T_C=25 °C
Operating and storage temperature	T_j, T_{stg}	-55	-	175	°C	IEC climatic category; DIN IEC 68-1: 55/175/56

3 Thermal characteristics

Table 3 Thermal characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Thermal resistance, junction - case	R_{thJC}	-	0.3	0.4	K/W	-
Thermal resistance, junction - ambient, minimal footprint	R_{thJA}	-	-	62	K/W	-
Thermal resistance, junction - ambient, 6 cm^2 cooling area[3]	R_{thJA}	-	-	40	K/W	-
Soldering temperature and reflow soldering is allowed	T_{sold}	-	-	260	°C	Reflow MSL1

[1] See Diagram 3 for more detailed information
[2] See Diagram 13 for more detailed information
[3] Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm^2 (one layer, 70 µm thick) copper area for drain connection. PCB is vertical in still air.

4 Electrical characteristics

Table 4 Static characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Drain-source breakdown voltage	$V_{(BR)DSS}$	80	-	-	V	V_{GS}=0 V, I_D=1 mA
Gate threshold voltage	$V_{GS(th)}$	2.2	3	3.8	V	V_{DS}=V_{GS}, I_D=279 µA
Zero gate voltage drain current	I_{DSS}	- -	0.1 10	1 100	µA	V_{DS}=80 V, V_{GS}=0 V, T_j=25 °C V_{DS}=80 V, V_{GS}=0 V, T_j=125 °C
Gate-source leakage current	I_{GSS}	-	1	100	nA	V_{GS}=20 V, V_{DS}=0 V
Drain-source on-state resistance	$R_{DS(on)}$	- -	1.1 1.5	1.5 1.8	mΩ	V_{GS}=10 V, I_D=100 A V_{GS}=6 V, I_D=50 A
Gate resistance [1]	R_G	-	1.5	2.3	Ω	-
Transconductance	g_{fs}	123	245	-	S	$\|V_{DS}\|>2\|I_D\|R_{DS(on)max}$, I_D=100 A

Table 5 Dynamic characteristics[1]

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Input capacitance	C_{iss}	-	13000	16900	pF	V_{GS}=0 V, V_{DS}=40 V, f=1 MHz
Output capacitance	C_{oss}	-	2000	2600	pF	V_{GS}=0 V, V_{DS}=40 V, f=1 MHz
Reverse transfer capacitance	C_{rss}	-	86	150	pF	V_{GS}=0 V, V_{DS}=40 V, f=1 MHz
Turn-on delay time	$t_{d(on)}$	-	33	-	ns	V_{DD}=40 V, V_{GS}=10 V, I_D=100 A, $R_{G,ext}$=1.6 Ω
Rise time	t_r	-	32	-	ns	V_{DD}=40 V, V_{GS}=10 V, I_D=100 A, $R_{G,ext}$=1.6 Ω
Turn-off delay time	$t_{d(off)}$	-	83	-	ns	V_{DD}=40 V, V_{GS}=10 V, I_D=100 A, $R_{G,ext}$=1.6 Ω
Fall time	t_f	-	28	-	ns	V_{DD}=40 V, V_{GS}=10 V, I_D=100 A, $R_{G,ext}$=1.6 Ω

Table 6 Gate charge characteristics[2]

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Gate to source charge	Q_{gs}	-	56	-	nC	V_{DD}=40 V, I_D=100 A, V_{GS}=0 to 10 V
Gate to drain charge[1]	Q_{gd}	-	37	56	nC	V_{DD}=40 V, I_D=100 A, V_{GS}=0 to 10 V
Switching charge	Q_{sw}	-	58	-	nC	V_{DD}=40 V, I_D=100 A, V_{GS}=0 to 10 V
Gate charge total[1]	Q_g	-	178	222	nC	V_{DD}=40 V, I_D=100 A, V_{GS}=0 to 10 V
Gate plateau voltage	$V_{plateau}$	-	4.5	-	V	V_{DD}=40 V, I_D=100 A, V_{GS}=0 to 10 V
Gate charge total, sync. FET	$Q_{g(sync)}$	-	153	-	nC	V_{DS}=0.1 V, V_{GS}=0 to 10 V
Output charge[1]	Q_{oss}	-	207	276	nC	V_{DD}=40 V, V_{GS}=0 V

[1] Defined by design. Not subject to production test.
[2] See "Gate charge waveforms" for parameter definition

Table 7 Reverse diode

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Diode continous forward current	I_S	-	-	180	A	T_C=25 °C
Diode pulse current	$I_{S,pulse}$	-	-	720	A	T_C=25 °C
Diode forward voltage	V_{SD}	-	0.86	1.2	V	V_{GS}=0 V, I_F=100 A, T_j=25 °C
Reverse recovery time[1]	t_{rr}	-	94	188	ns	V_R=40 V, I_F=100 A, di_F/dt=100 A/µs
Reverse recovery charge[1]	Q_{rr}	-	246	492	nC	V_R=40 V, I_F=100 A, di_F/dt=100 A/µs

[1] Defined by design. Not subject to production test.

5 Electrical characteristics diagrams

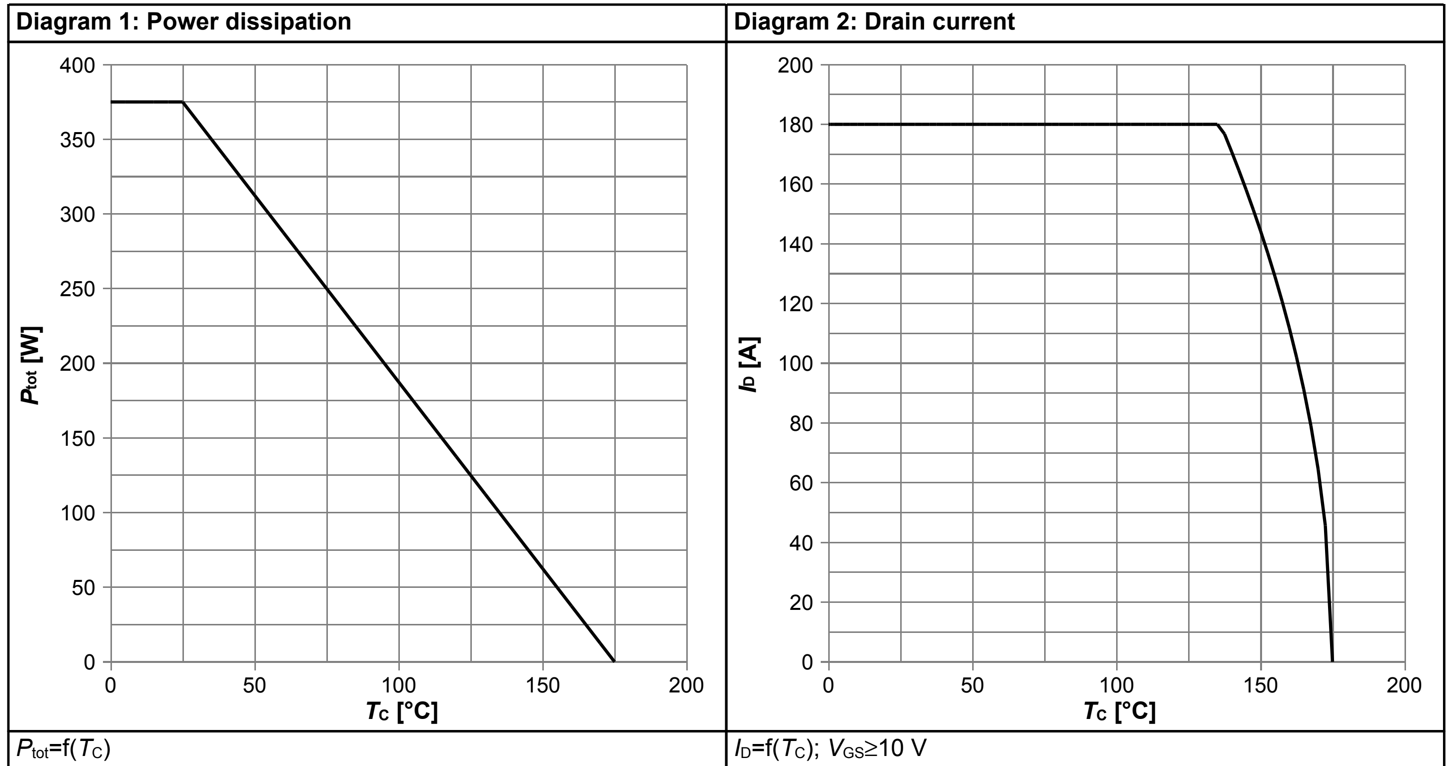


Diagram 1: Power dissipation — P_{tot}=f(T_C)

Diagram 2: Drain current — I_D=f(T_C); V_{GS}≥10 V

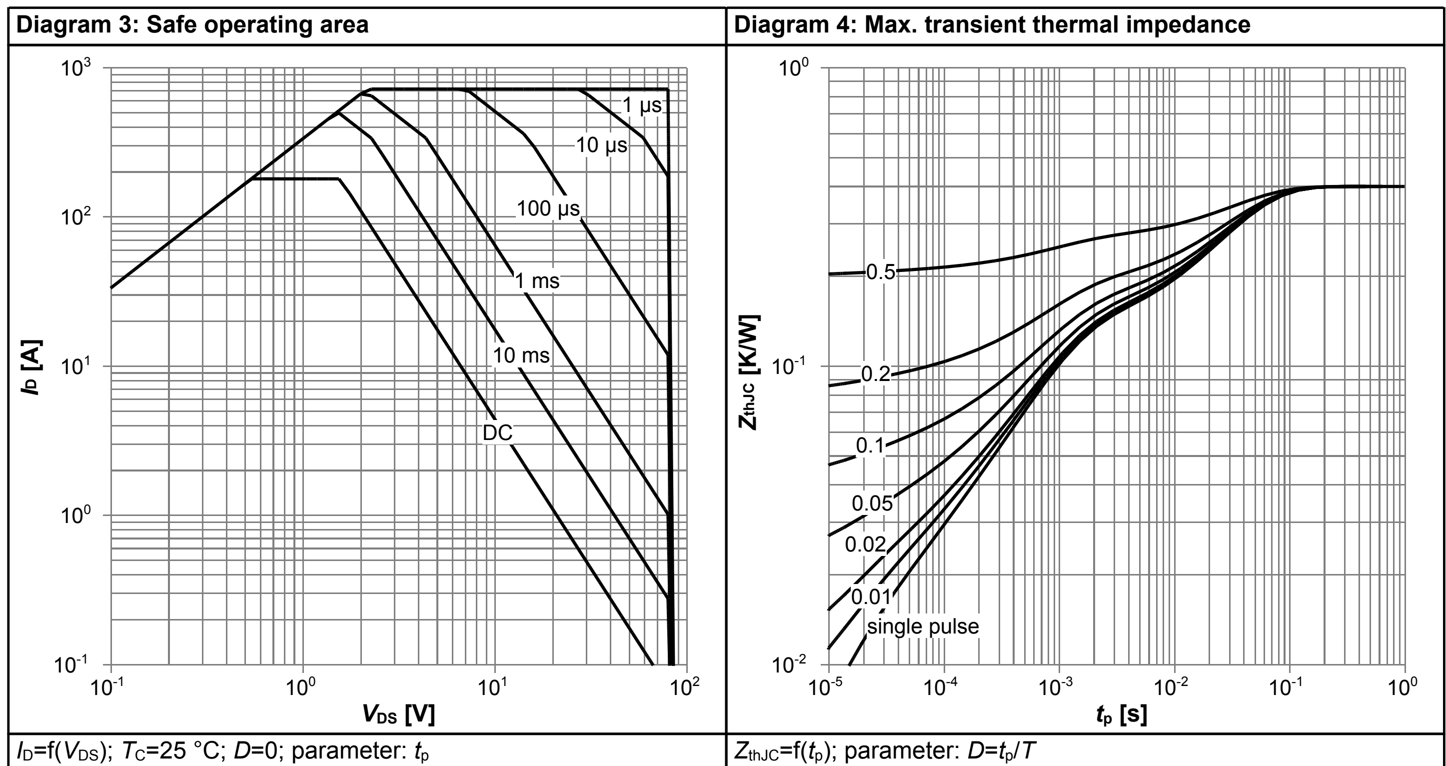
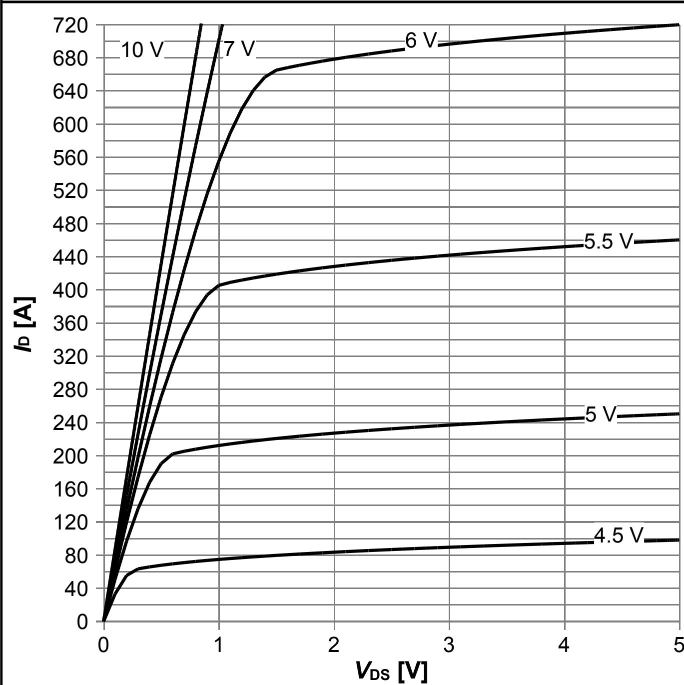


Diagram 3: Safe operating area — I_D=f(V_{DS}); T_C=25 °C; D=0; parameter: t_p

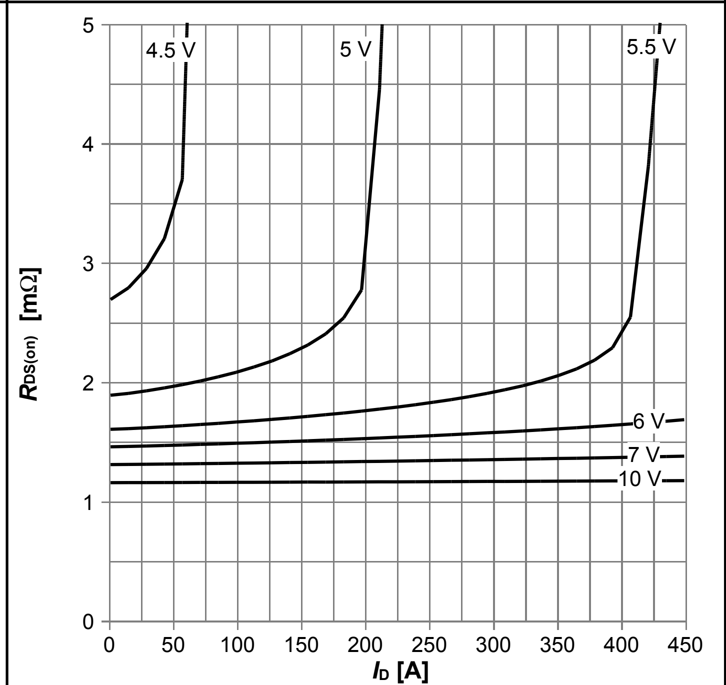
Diagram 4: Max. transient thermal impedance — Z_{thJC}=f(t_p); parameter: D=t_p/T

Diagram 5: Typ. output characteristics



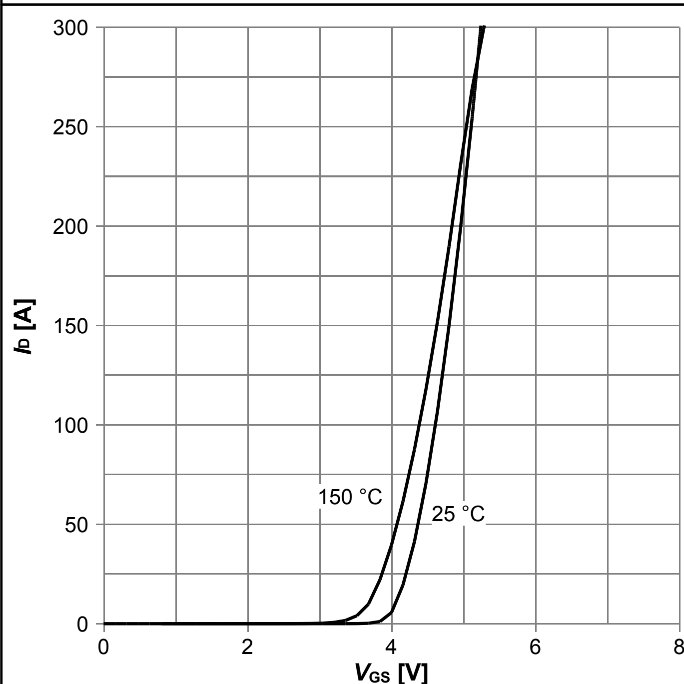
I_D=f(V_{DS}); T_j=25 °C; parameter: V_{GS}

Diagram 6: Typ. drain-source on resistance



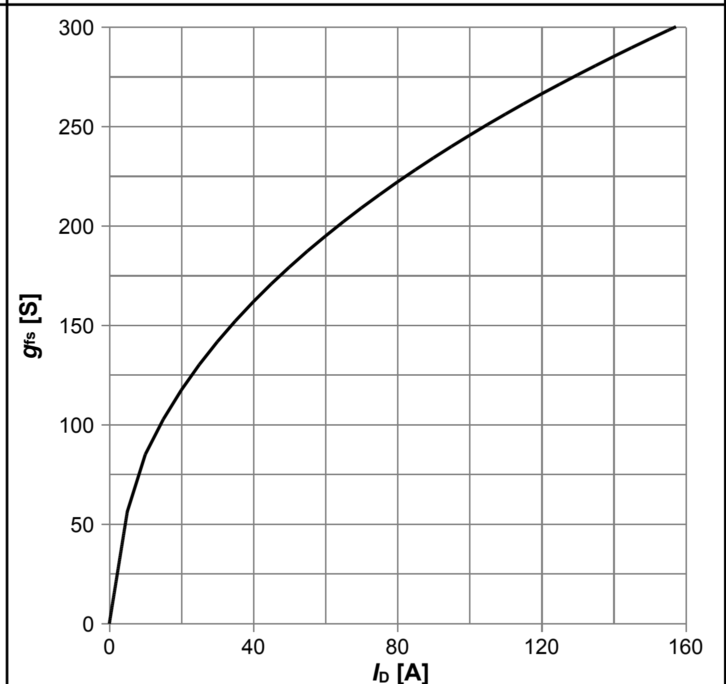
$R_{DS(on)}$=f(I_D); T_j=25 °C; parameter: V_{GS}

Diagram 7: Typ. transfer characteristics



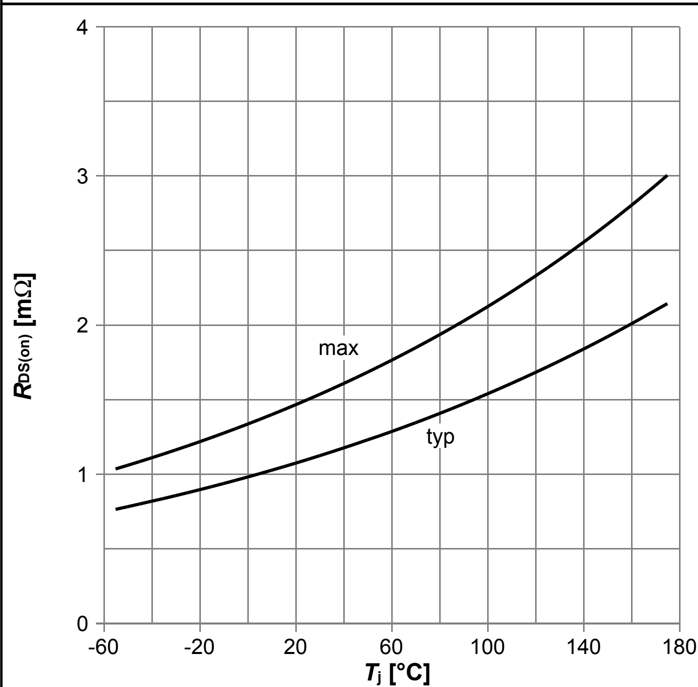
I_D=f(V_{GS}); $|V_{DS}|$>2$|I_D|R_{DS(on)max}$; parameter: T_j

Diagram 8: Typ. forward transconductance



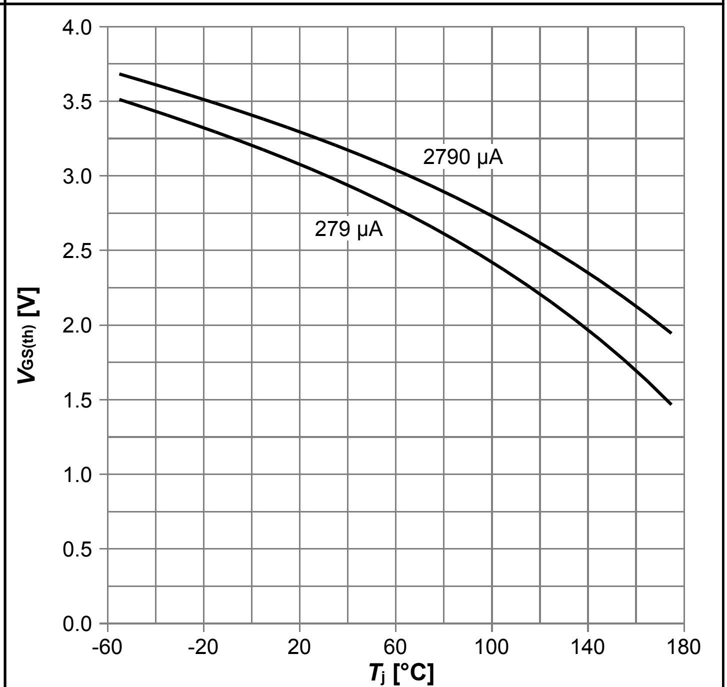
g_{fs}=f(I_D); T_j=25 °C

Diagram 9: Drain-source on-state resistance



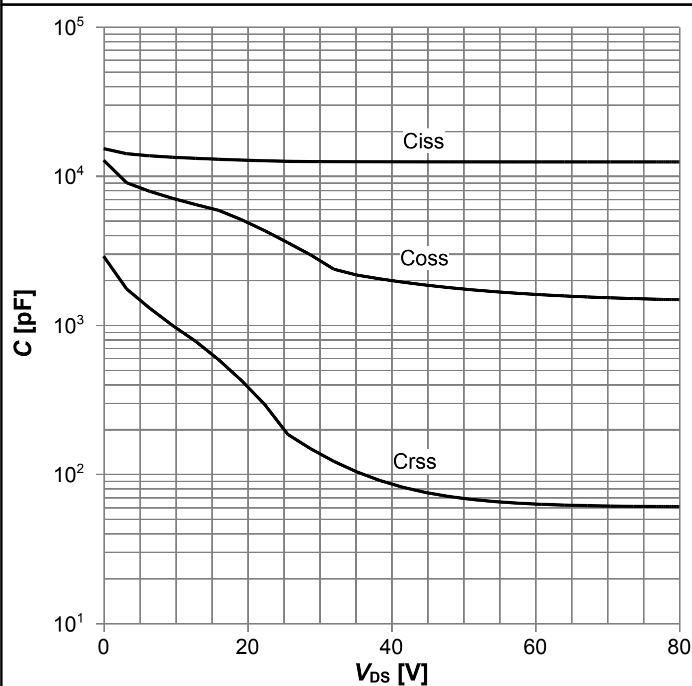
$R_{DS(on)}$=f(T_j); I_D=100 A; V_{GS}=10 V

Diagram 10: Typ. gate threshold voltage



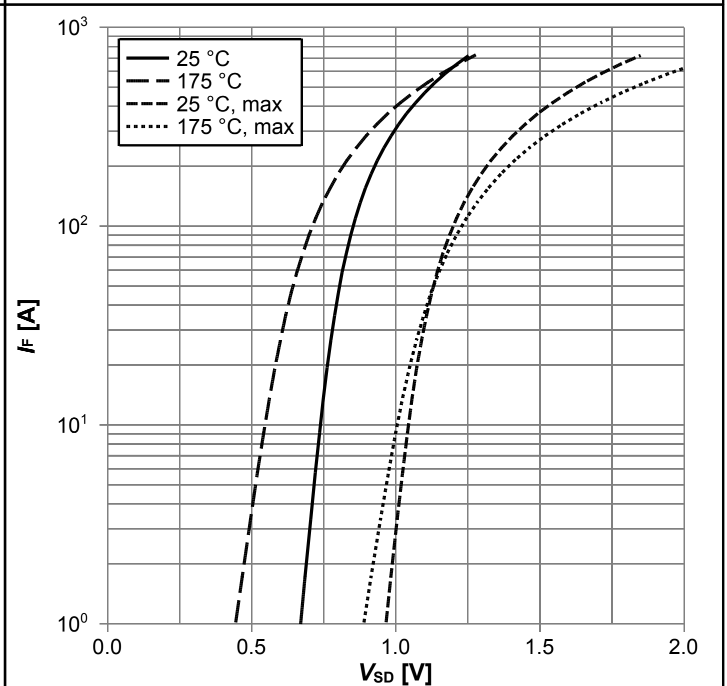
$V_{GS(th)}$=f(T_j); V_{GS}=V_{DS}; parameter: I_D

Diagram 11: Typ. capacitances



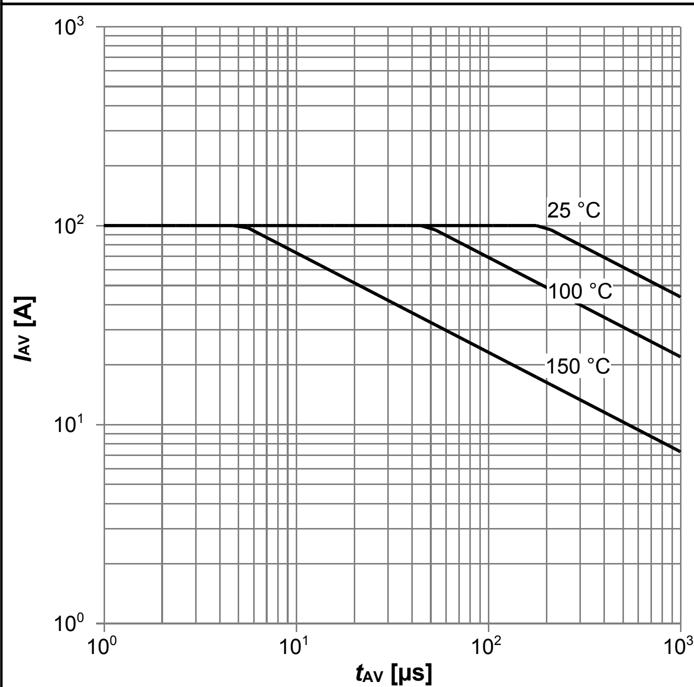
C=f(V_{DS}); V_{GS}=0 V; f=1 MHz

Diagram 12: Forward characteristics of reverse diode



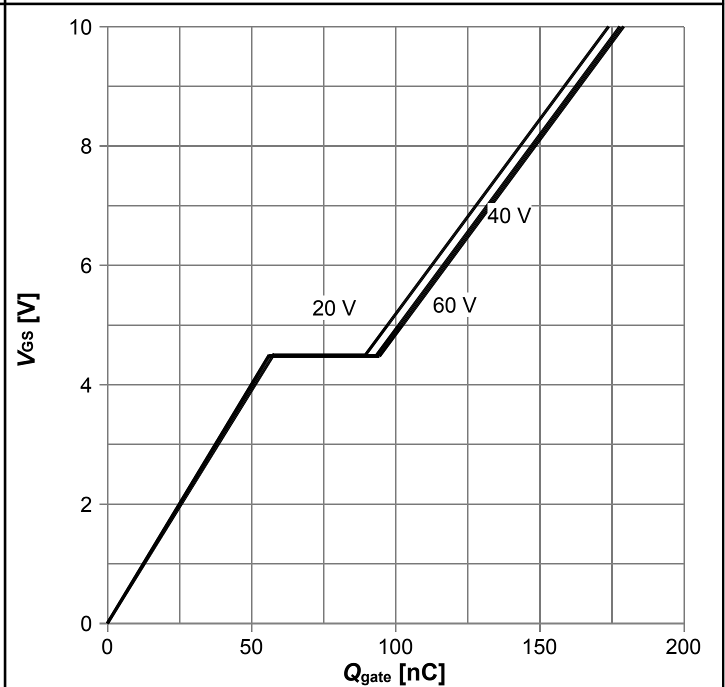
I_F=f(V_{SD}); parameter: T_j

Diagram 13: Avalanche characteristics



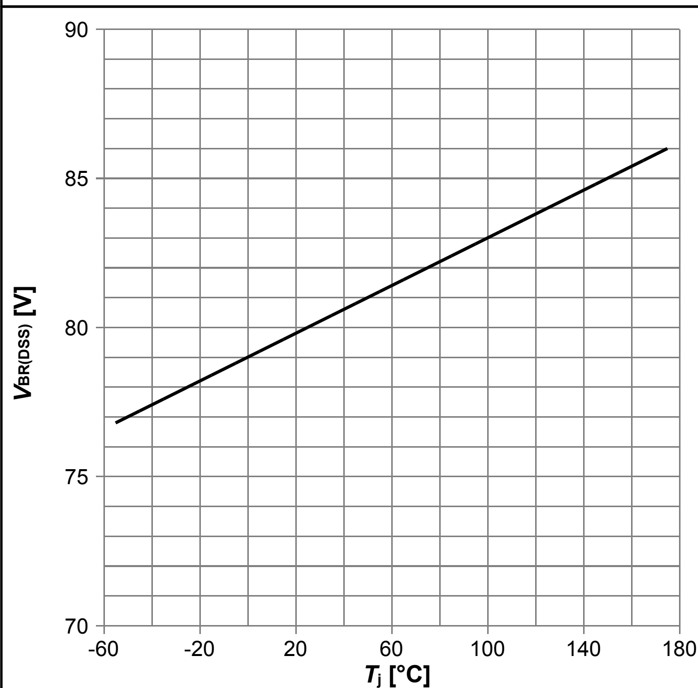
I_{AS}=f(t_{AV}); R_{GS}=25 Ω; parameter: $T_{j(start)}$

Diagram 14: Typ. gate charge



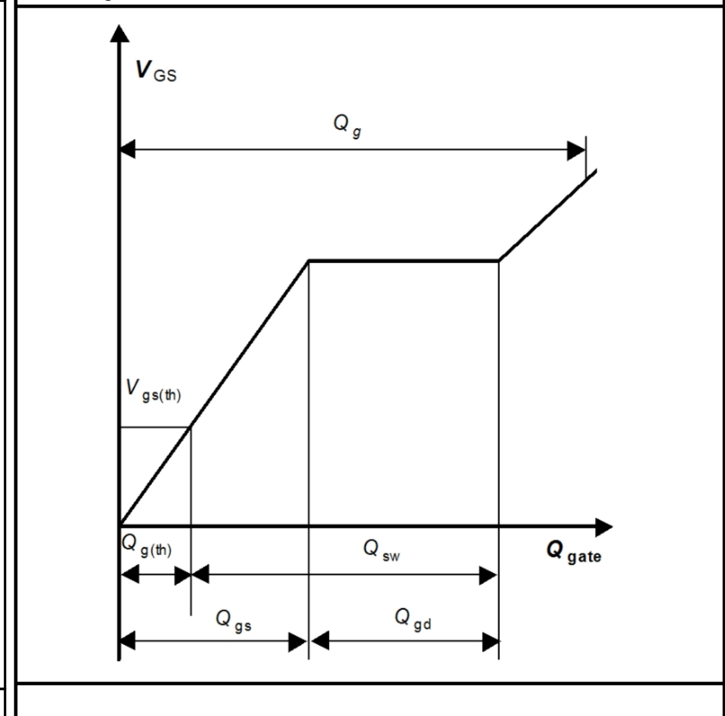
V_{GS}=f(Q_{gate}); I_D=100 A pulsed; parameter: V_{DD}

Diagram 15: Drain-source breakdown voltage

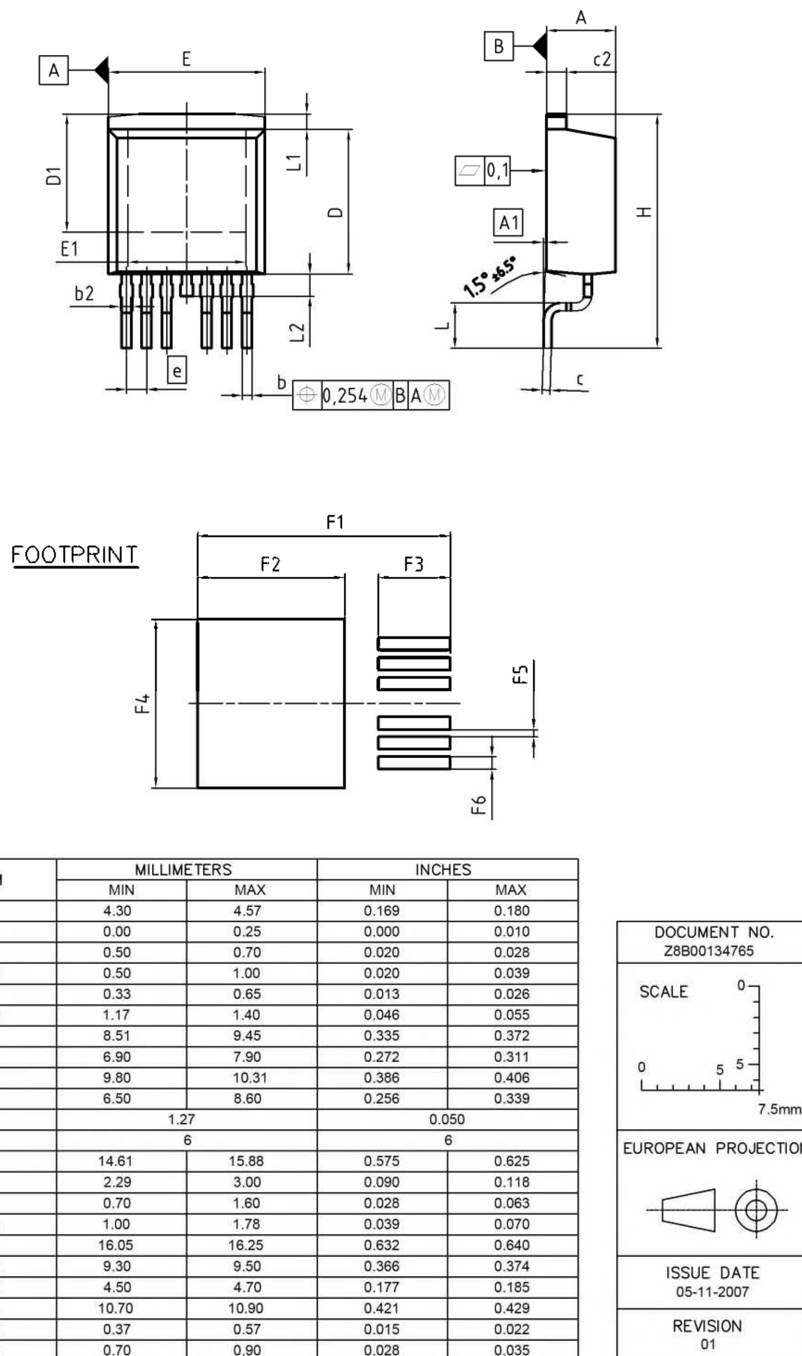


$V_{BR(DSS)}$=f(T_j); I_D=1 mA

Gate charge waveforms



6 Package Outlines



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.30	4.57	0.169	0.180
A1	0.00	0.25	0.000	0.010
b	0.50	0.70	0.020	0.028
b2	0.50	1.00	0.020	0.039
c	0.33	0.65	0.013	0.026
c2	1.17	1.40	0.046	0.055
D	8.51	9.45	0.335	0.372
D1	6.90	7.90	0.272	0.311
E	9.80	10.31	0.386	0.406
E1	6.50	8.60	0.256	0.339
e	1.27		0.050	
N	6		6	
H	14.61	15.88	0.575	0.625
L	2.29	3.00	0.090	0.118
L1	0.70	1.60	0.028	0.063
L2	1.00	1.78	0.039	0.070
F1	16.05	16.25	0.632	0.640
F2	9.30	9.50	0.366	0.374
F3	4.50	4.70	0.177	0.185
F4	10.70	10.90	0.421	0.429
F5	0.37	0.57	0.015	0.022
F6	0.70	0.90	0.028	0.035

Figure 1 Outline PG-TO263-7, dimensions in mm/inches

Revision History

IPB015N08N5

Revision: 2015-10-15, Rev. 2.1

Previous Revision		
Revision	Date	Subjects (major changes since last revision)
2.0	2014-12-11	Release of final version
2.1	2015-10-15	Update package Outline

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